

# ZXMN6A09K 60V N-channel enhancement mode MOSFET in DPAK

## **Summary**

 $V_{(BR)DSS}$ =60 $V: R_{DS(on)}$ =0.040 $\Omega$ ;  $I_D$ =12.2A

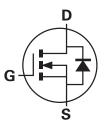
# Description

This new generation of trench MOSFETs from Zetex utilizes a unique structure that combines the benefits of low on-resistance with fast switching speed. This makes them ideal for high efficiency, low voltage power management applications.



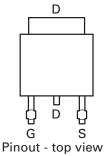
## **Features**

- · Low on-resistance
- · Fast switching speed
- · Low threshold
- · Low gate drive
- DPAK (T0-252) package



## **Applications**

- · DC-DC converters
- · Power management functions
- · Disconnect switches
- · Motor control



## **Ordering information**

Device	Reel size (inches)	Tape width (mm)	Quantity per reel	
ZXMN6A09KTC	13	16	2500	

## **Device marking**

ZXMN 6A09K

## **Absolute maximum ratings**

Parameter	Symbol	Limit	Unit
Drain-source voltage	$V_{DSS}$	60	V
Gate-source voltage	$V_{GS}$	±20	V
Continuous drain current @ V <sub>GS</sub> =10V; T <sub>amb</sub> =25°C <sup>(b)</sup>	I <sub>D</sub>	12.2	Α
@ V <sub>GS</sub> =10V; T <sub>amb</sub> =70°C <sup>(b)</sup>		9.8	
@ V <sub>GS</sub> =10V; T <sub>amb</sub> =25°C <sup>(a)</sup>		7.9	
Pulsed drain current <sup>(c)</sup>	I <sub>DM</sub>	43	Α
Continuous source current (body diode)(b)	I <sub>S</sub>	10.8	Α
Pulsed source current (body diode)(c)	I <sub>SM</sub>	43	Α
Power dissipation at T <sub>amb</sub> =25°C <sup>(a)</sup>	$P_{D}$	4.3	W
Linear derating factor		34.4	mW/°C
Power dissipation at T <sub>amb</sub> =25°C <sup>(a)</sup>	$P_{D}$	10.1	W
Linear derating factor		80.8	mW/°C
Power dissipation at T <sub>amb</sub> =25°C <sup>(a)</sup>	$P_{D}$	2.15	W
Linear derating factor		17.2	mW/°C
Operating and storage temperature range	T <sub>j</sub> , T <sub>stg</sub>	-55 to +150	°C

## Thermal resistance

Parameter	Symbol	Limit	Unit
Junction to ambient <sup>(a)</sup>	$R_{\Theta JA}$	29	°C/W
Junction to ambient <sup>(b)</sup>	$R_{\Theta JA}$	12.3	°C/W
Junction to ambient <sup>(d)</sup>	$R_{\Theta JA}$	58.1	°C/W

### NOTES:

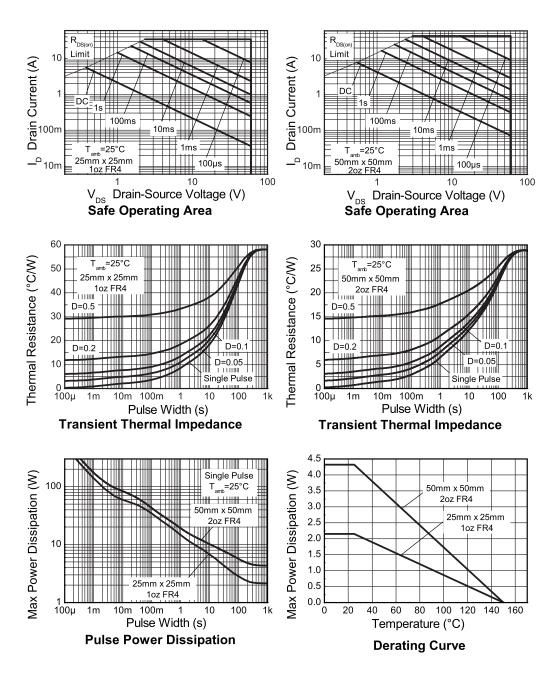
<sup>(</sup>a) For a device surface mounted on 50mm x 50mm x 1.6mm FR4 PCB with high coverage of single sided 2oz copper, in still air conditions.

<sup>(</sup>b) For a device surface mounted on FR4 PCB measured at t  $\leq\!10$  sec.

<sup>(</sup>c) Repetitive rating 50mm x 50mm x 1.6mm FR4 PCB, D=0.02 pulse width=300 $\mu$ s - pulse width limited by maximum junction temperature.

<sup>(</sup>d) For a device surface mounted on 25mm x 25mm x 1.6mm FR4 PCB with high coverage of single sided 1oz copper, in still air conditions.

## **Characteristics**



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# Electrical characteristics (at $T_{amb} = 25$ °C unless otherwise stated)

Parameter	Symbol	Min.	Тур.	Max.	Unit	Conditions
Static	•	•				
Drain-source breakdown voltage	V <sub>(BR)DSS</sub>	60			V	I <sub>D</sub> = 250μA, V <sub>GS</sub> =0V
Zero gate voltage drain current	I <sub>DSS</sub>			1	μΑ	V <sub>DS</sub> = 60V, V <sub>GS</sub> =0V
Gate-body leakage	I <sub>GSS</sub>			100	nA	V <sub>GS</sub> =±20V, V <sub>DS</sub> =0V
Gate-source threshold voltage	V <sub>GS(th)</sub>	1.0		3.0	V	I <sub>D</sub> = 250μA, V <sub>DS</sub> =V <sub>GS</sub>
Static drain-source on-state	R <sub>DS(on)</sub>			0.040	Ω	V <sub>GS</sub> = 10V, I <sub>D</sub> = 7.3A
resistance (*)				0.060	Ω	V <sub>GS</sub> = 4.5V, I <sub>D</sub> = 5.6A
Forward transconductance(*)(‡)	9 <sub>fs</sub>		15		S	V <sub>DS</sub> = 15V, I <sub>D</sub> = 7.3A
Dynamic <sup>(‡)</sup>	•					
Input capacitance	C <sub>iss</sub>		1426		рF	V <sub>DS</sub> = 30V, V <sub>GS</sub> =0V
Output capacitance	C <sub>oss</sub>		134		pF	f=1MHz
Reverse transfer capacitance	C <sub>rss</sub>		64		pF	
Switching (†) (‡)		I	I	I		1
Turn-on-delay time	t <sub>d(on)</sub>		4.8		ns	V <sub>DD</sub> = 30V, I <sub>D</sub> = 1A
Rise time	t <sub>r</sub>		4.6		ns	$R_{G} = 6.0\Omega$ , $V_{GS} = 10V$
Turn-off delay time	t <sub>d(off)</sub>		32.5		ns	(refer to test circuit)
Fall time	t <sub>f</sub>		14.5		ns	
Total gate charge	$Q_g$		15		nC	V <sub>DS</sub> = 30V, V <sub>GS</sub> = 4.5V I <sub>D</sub> = 5.6A
Total gate charge	Qg		29		nC	V <sub>DS</sub> = 30V, V <sub>GS</sub> = 10V
Gate-source charge	O <sub>gs</sub>		7.0		nC	I <sub>D</sub> = 7.3A
Gate drain charge	$Q_{gd}$		4.7		nC	
Source-drain diode	ı	I	I	I		
Diode forward voltage <sup>(*)</sup>	V <sub>SD</sub>		0.85	0.95	V	T <sub>j</sub> =25°C, I <sub>S</sub> = 6.6A, V <sub>GS</sub> =0V
Reverse recovery time(‡)	t <sub>rr</sub>		25.6		ns	T <sub>j</sub> =25°C, I <sub>S</sub> = 3A,
Reverse Recovery charge <sup>(‡)</sup>	Q <sub>rr</sub>		26.0		nC	di/dt=100A/μs

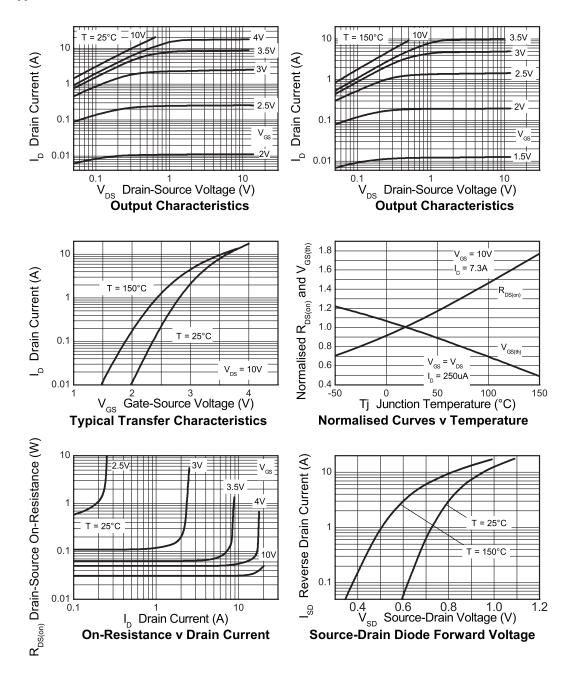
## NOTES:

<sup>(\*)</sup> Measured under pulsed conditions. Pulse width  $\leq$ 300 s; duty cycle  $\leq$ 2%.

<sup>(†)</sup> Switching characteristics are independent of operating junction temperature.

<sup>(‡)</sup> For design aid only, not subject to production testing.

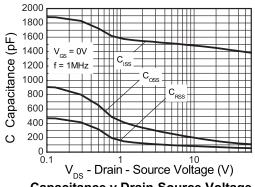
## **Typical characteristics**

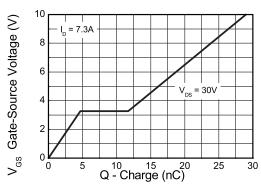


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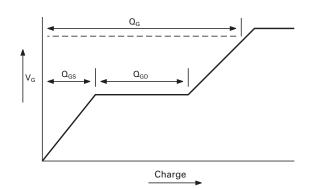
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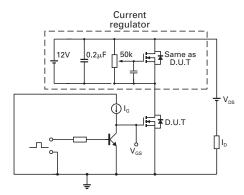




Capacitance v Drain-Source Voltage

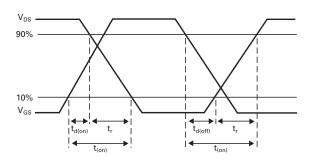
Gate-Source Voltage v Gate Charge

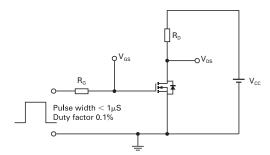




Basic gate charge waveform

Gate charge test circuit





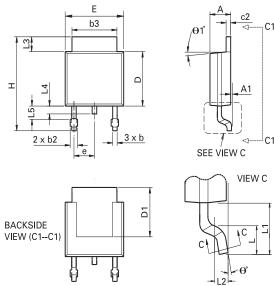
**Switching time waveforms** 

Switching time test circuit

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# **ZXMN6A09K**

# Package outline - DPAK



<del></del>										
DIM	Inc	hes	Millin	neters	DIM	Inches		Millimeters		
	Min	Max	Min	Max		Min	Max	Min	Max	
Α	0.086	0.094	2.18	2.39	е	0.090	0.090 BSC		2.29 BSC	
A1	-	0.005	-	0.127	Н	0.370	0.410	9.40	10.41	
b	0.020	0.035	0.508	0.89	L	0.055	0.070	1.40	1.78	
b2	0.030	0.045	0.762	1.14	L1	0.108	REF	2.74	REF	
b3	0.205	0.215	5.21	5.46	L2	0.020	) BSC	0.508	BSC	
С	0.018	0.024	0.457	0.61	L3	0.035	0.065	0.89	1.65	
c2	0.018	0.023	0.457	0.584	L4	0.025	0.040	0.635	1.016	
D	0.213	0.245	5.41	6.22	L5	0.045	0.060	1.14	1.52	
D1	0.205	-	5.21	-	θ1°	0°	10°	0°	10°	
Е	0.250	0.265	6.35	6.73	θ°	0°	15°	0°	15°	
E1	0.170	-	4.32	-	-	-	-	-	-	

Note: Controlling dimensions are in inches. Approximate dimensions are provided in millimeters

## ZXMN6A09K

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